
VE320 – Summer 2024

Introduction to Semiconductor Devices

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Chapter 8 The pn Junction Diode



Outline

8.1 pn junction current

8.2 Generation-recombination currents

8.3 High-injection levels

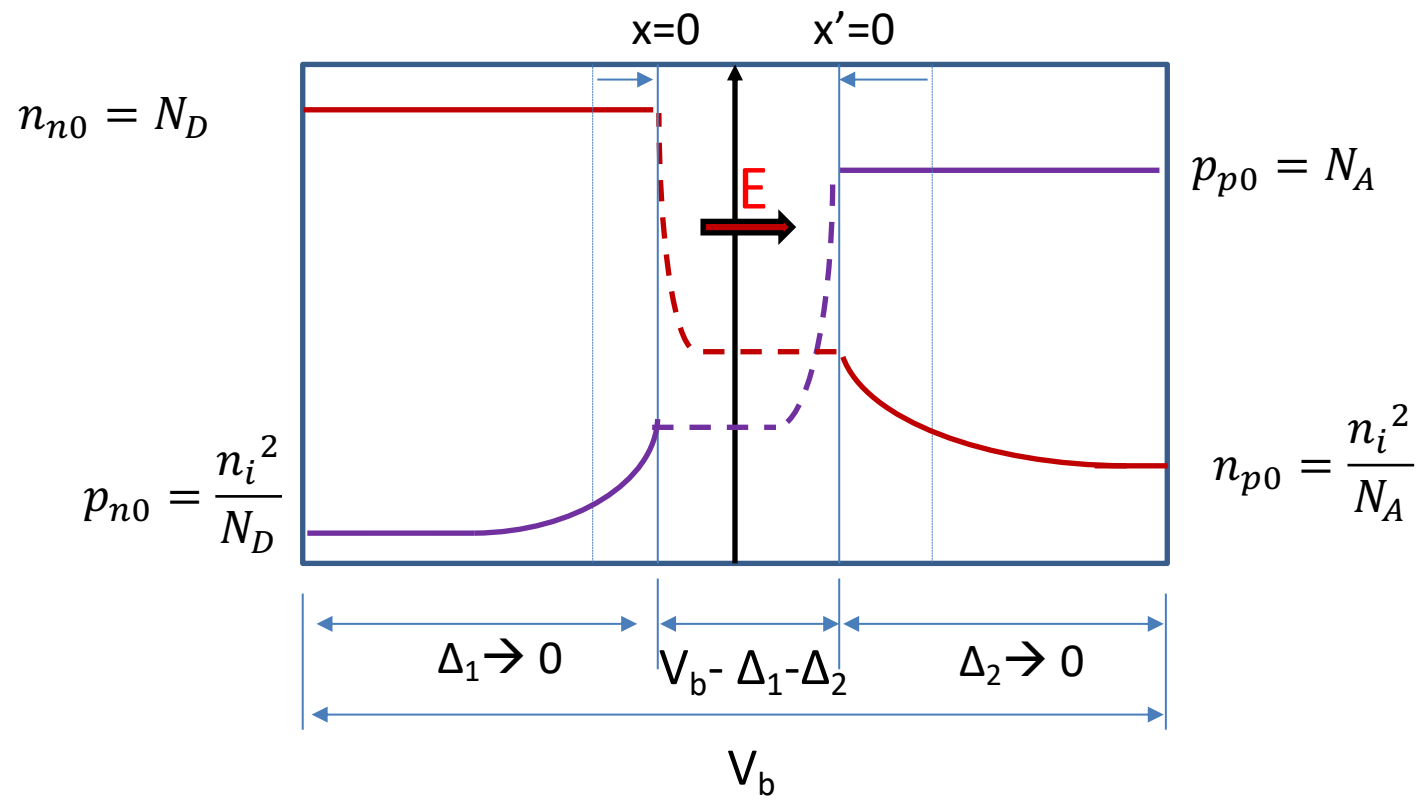
8.4 A few more points on pn junctions (not in the textbook)

8.0 The logic behind the way to derive current

Explain why there is no current flow when the pn junction is reverse biased.

What happens the pn junction is forward biased?

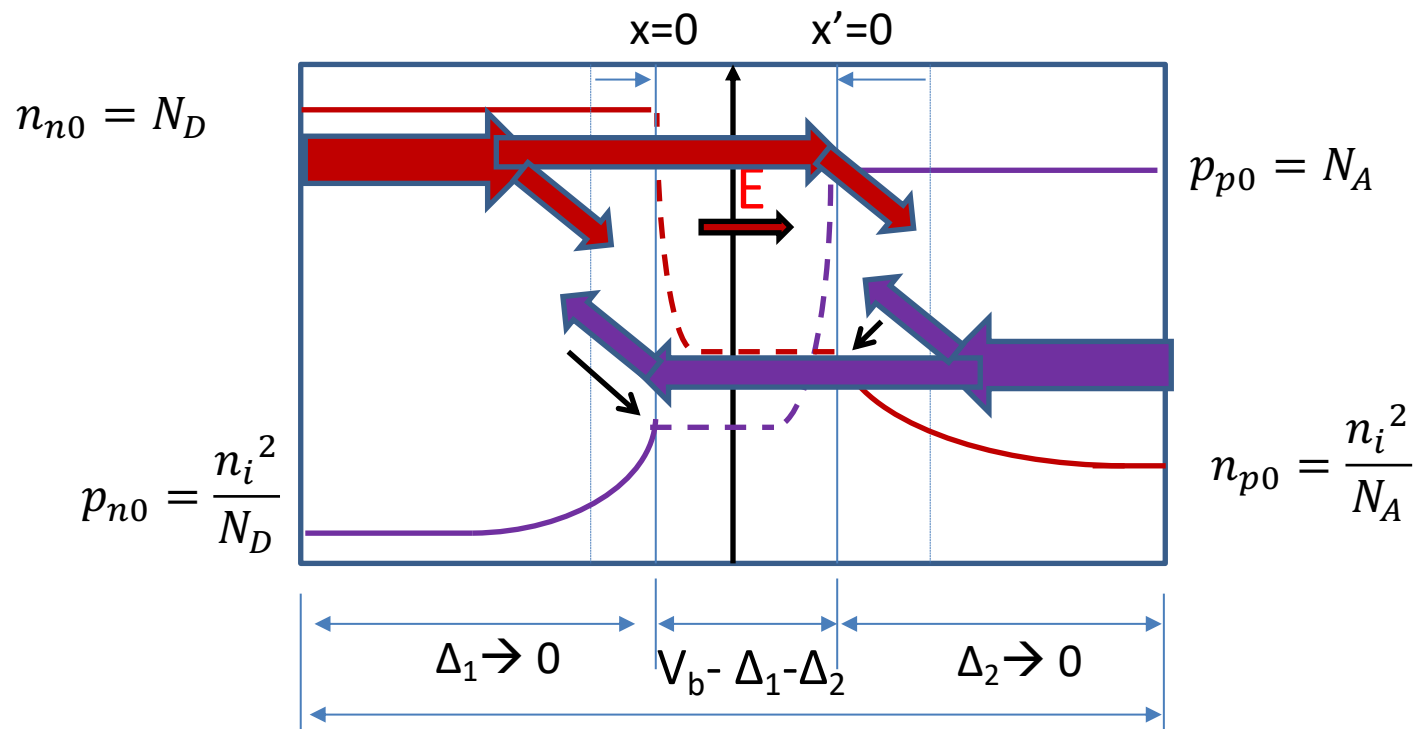
8.0 The logic behind the way to derive current



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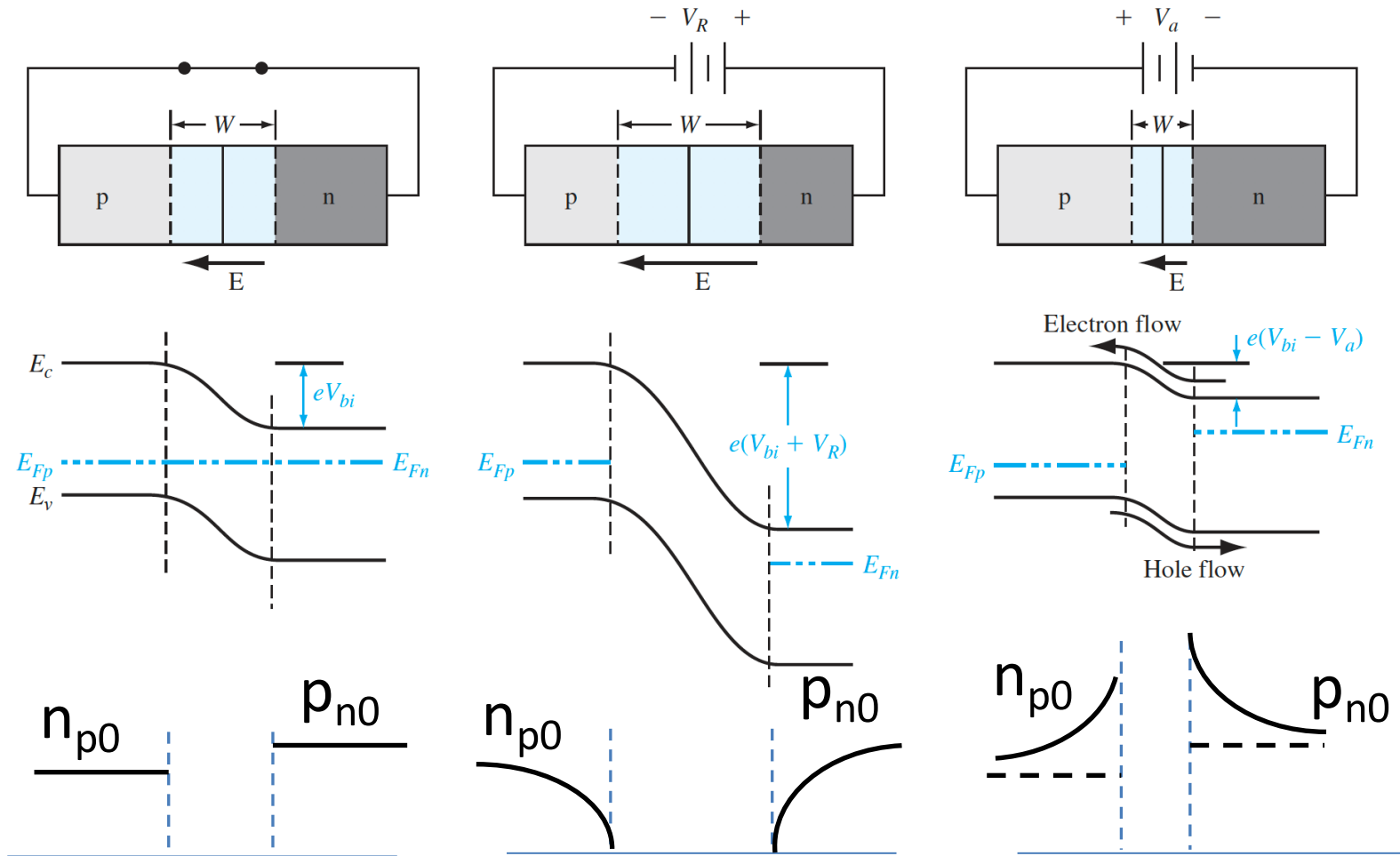
Total current I_t is uniform at every x

$$I_t = I_n(x=0) + I_h(x=0) = I_n(x'=0) + I_h(x'=0)$$



8.1 pn Junction Current

Qualitative Description of Charge Flow in a pn Junction



8.1 pn Junction Current

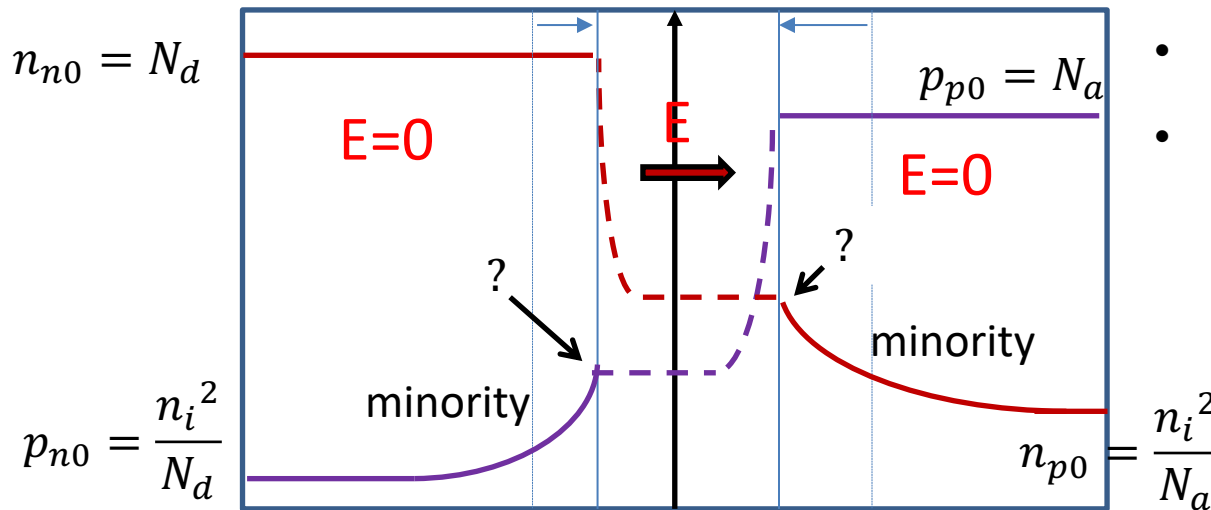
Goal: to find the analytical expression of current

$$\frac{\partial n}{\partial t} = D_n \frac{\partial^2 n}{\partial x^2} + \mu_n E \frac{\partial n}{\partial x} + n \mu_n \frac{\partial E}{\partial x} - \frac{\Delta n}{\tau} + G_{ex}$$

$$\frac{\partial p}{\partial t} = D_p \frac{\partial^2 p}{\partial x^2} - \mu_p E \frac{\partial p}{\partial x} - p \mu_p \frac{\partial E}{\partial x} - \frac{\Delta p}{\tau} + G_{ex}$$

Electrons as minority

holes as minority



- How to simplify?
- Boundary condition?
- how to get total current from minority currents?

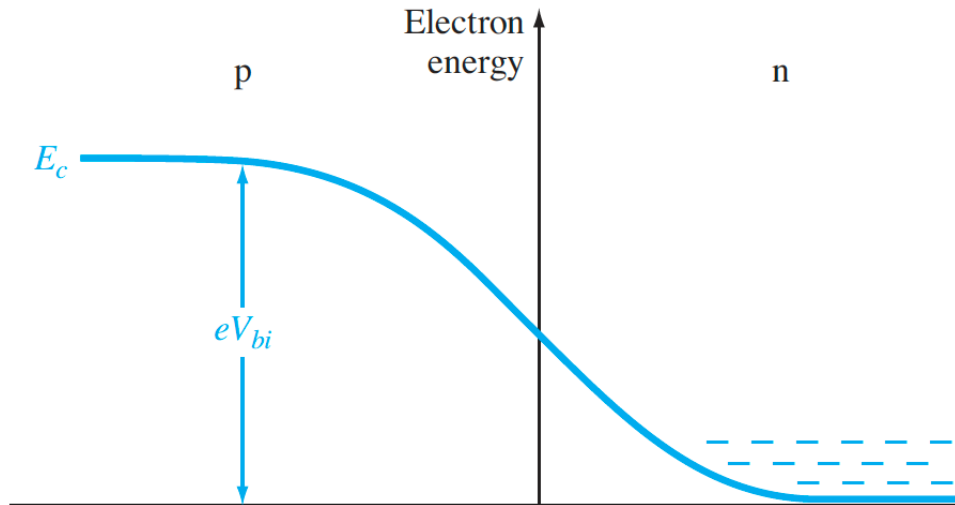
8.1 pn Junction Current

Assumptions of an ideal PN junction

1. The abrupt depletion layer approximation applies. The space charge regions have abrupt boundaries, and the semiconductor is neutral outside of the depletion region.
2. The Maxwell–Boltzmann approximation applies to carrier statistics.
3. The concepts of low injection and complete ionization apply.
- 4a. The total current is a constant throughout the entire pn structure.
- 4b. The individual electron and hole currents are continuous functions through the pn structure.
- 4c. The individual electron and hole currents are constant throughout the depletion region.

8.1 pn Junction Current

Boundary condition



$$V_{bi} = V_t \ln \left(\frac{N_a N_d}{n_i^2} \right)$$

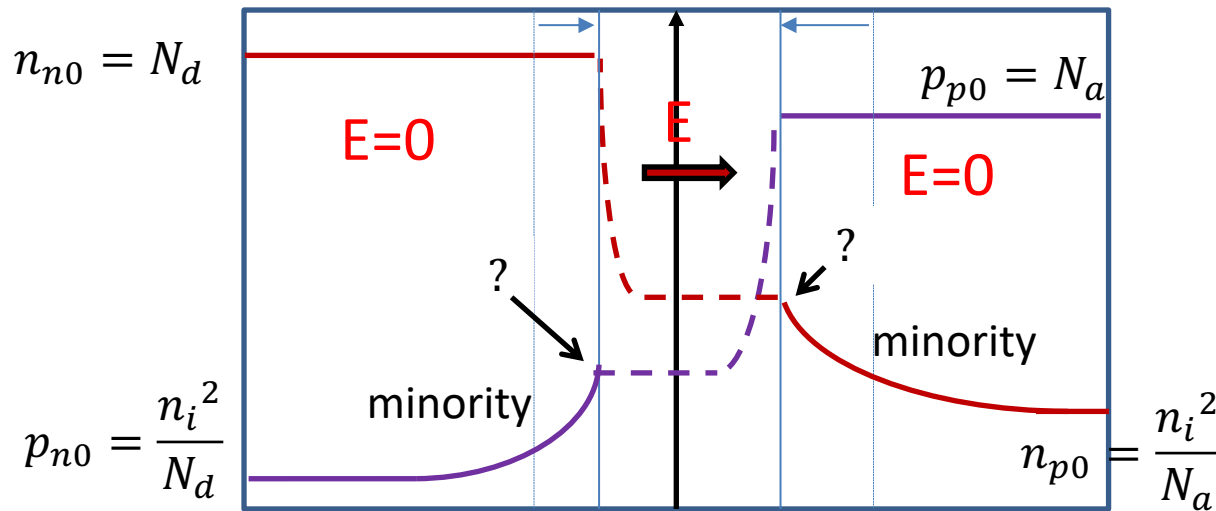
$$n_{p0} = n_{n0} \exp \left(\frac{-eV_{bi}}{kT} \right)$$

8.1 pn Junction Current

Boundary condition

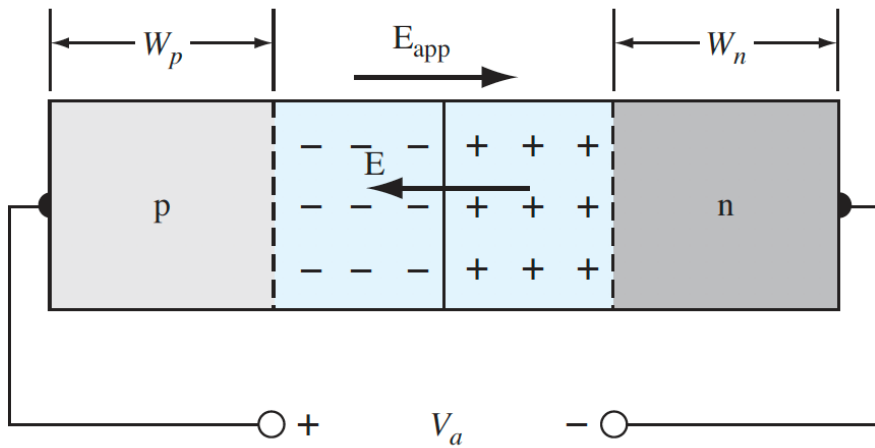
$$p_{n0} = p_{p0} \exp\left(\frac{-eV_{bi}}{kT}\right)$$

$$n_{p0} = n_{n0} \exp\left(\frac{-eV_{bi}}{kT}\right)$$

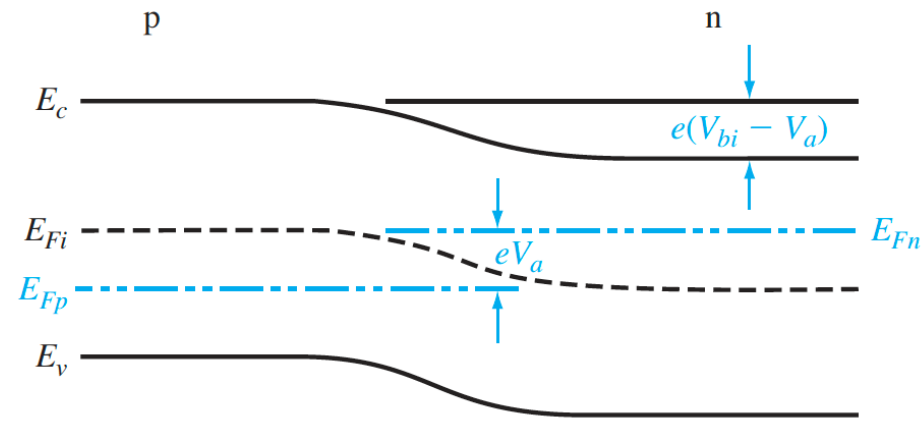


8.1 pn Junction Current

Boundary condition



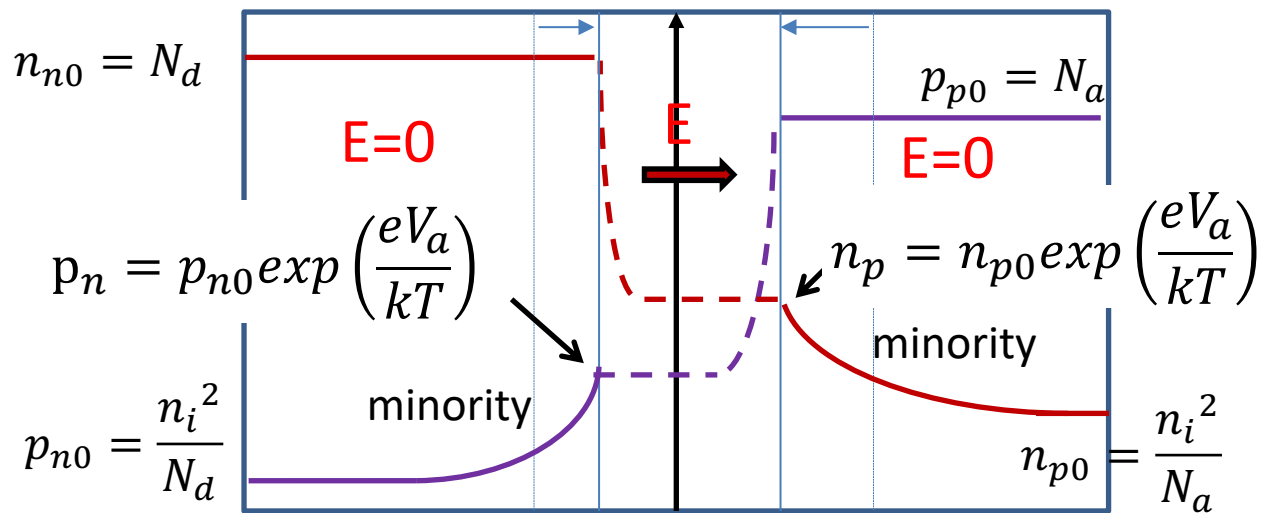
(a)



(b)

8.1 pn Junction Current

Boundary condition



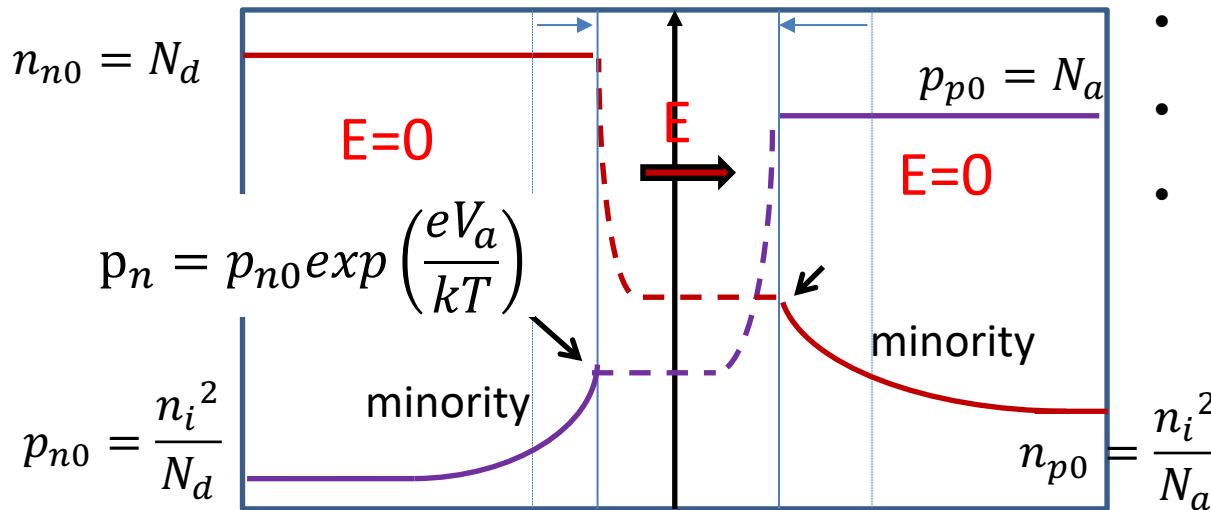
Check your understanding

Problem Example #1

Consider a silicon pn junction at $T = 300\text{K}$. Assume the doping concentration in the n region is $N_d = 10^{16} \text{ cm}^{-3}$ and the doping concentration in the p region is $N_a = 6 \times 10^{15} \text{ cm}^{-3}$. Assume a forward bias of 0.6V is applied to the pn junction. Calculate the minority concentration at the edge of the depletion region.

8.1 pn Junction Current

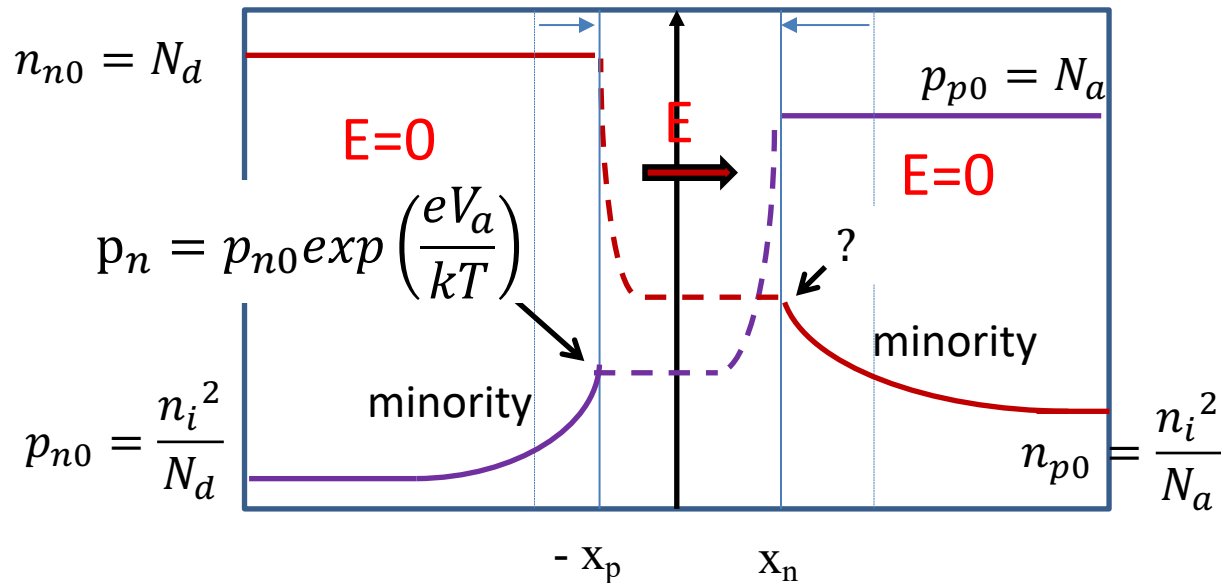
Minority carrier distribution (simplify continuity equation)



- How to simplify?
- Boundary condition?
- how to get total current from minority currents?

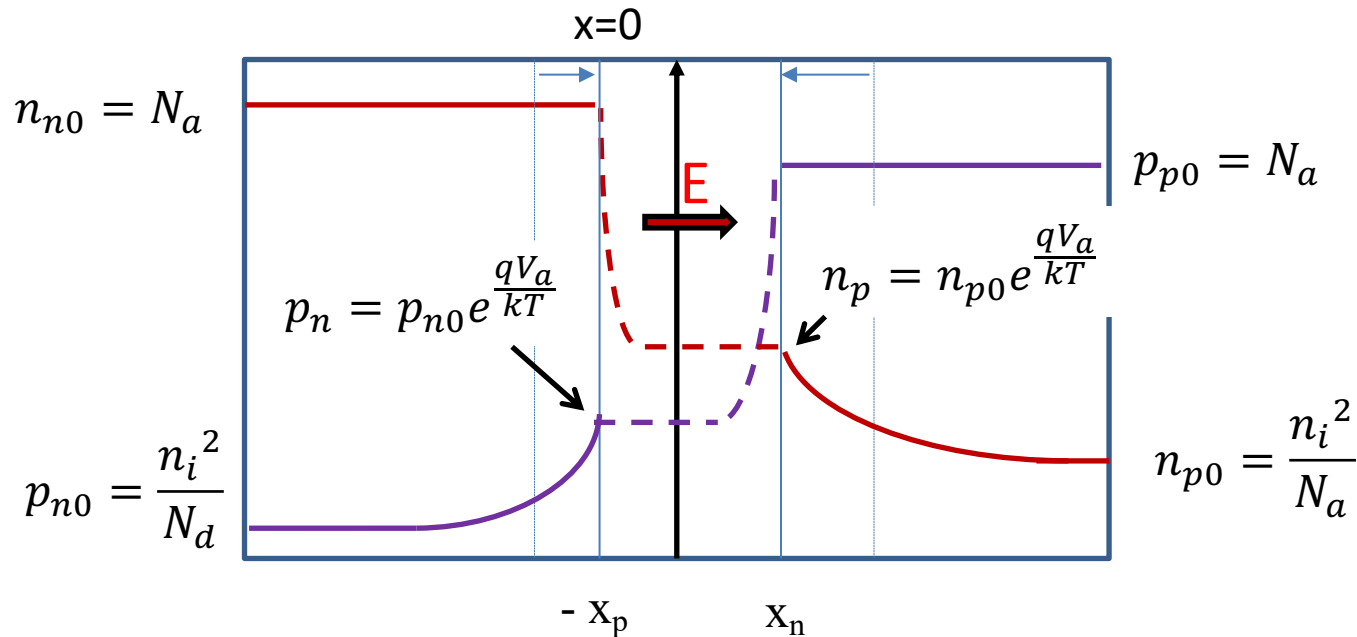
8.1 pn Junction Current

Minority carrier distribution (solution + boundary condition)



8.1 pn Junction Current

Minority carrier distribution (excess carriers)

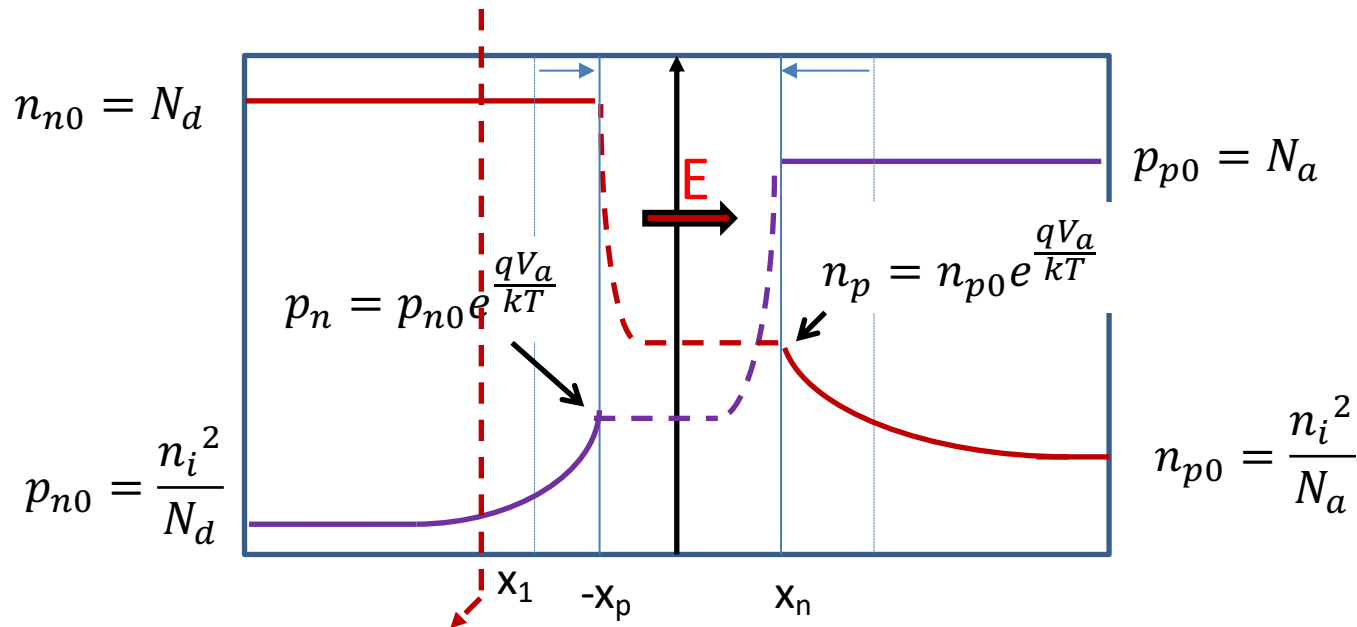


8.1 pn Junction Current

Minority carrier distribution

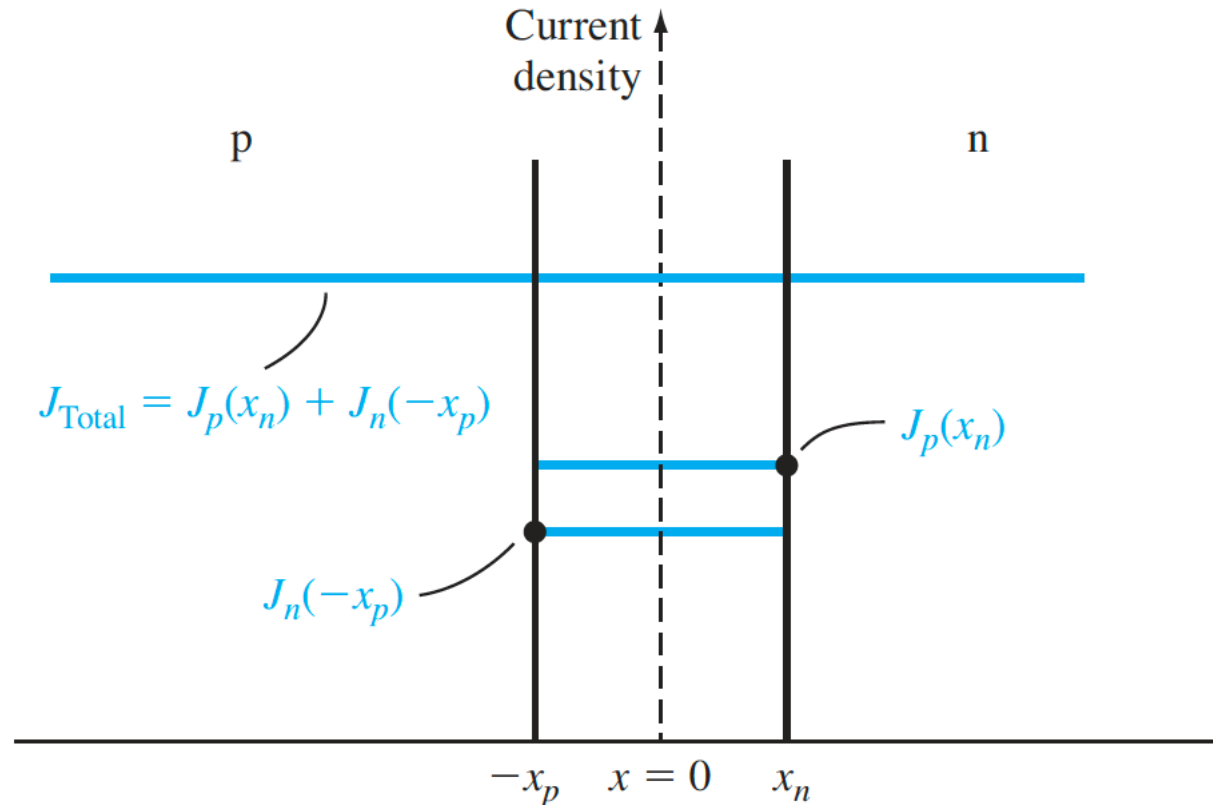
8.1 pn Junction Current

- charge carrier transport: current density



8.1 pn Junction Current

- Ideal pn junction current



Assumption: No recombination-generation in depletion region.

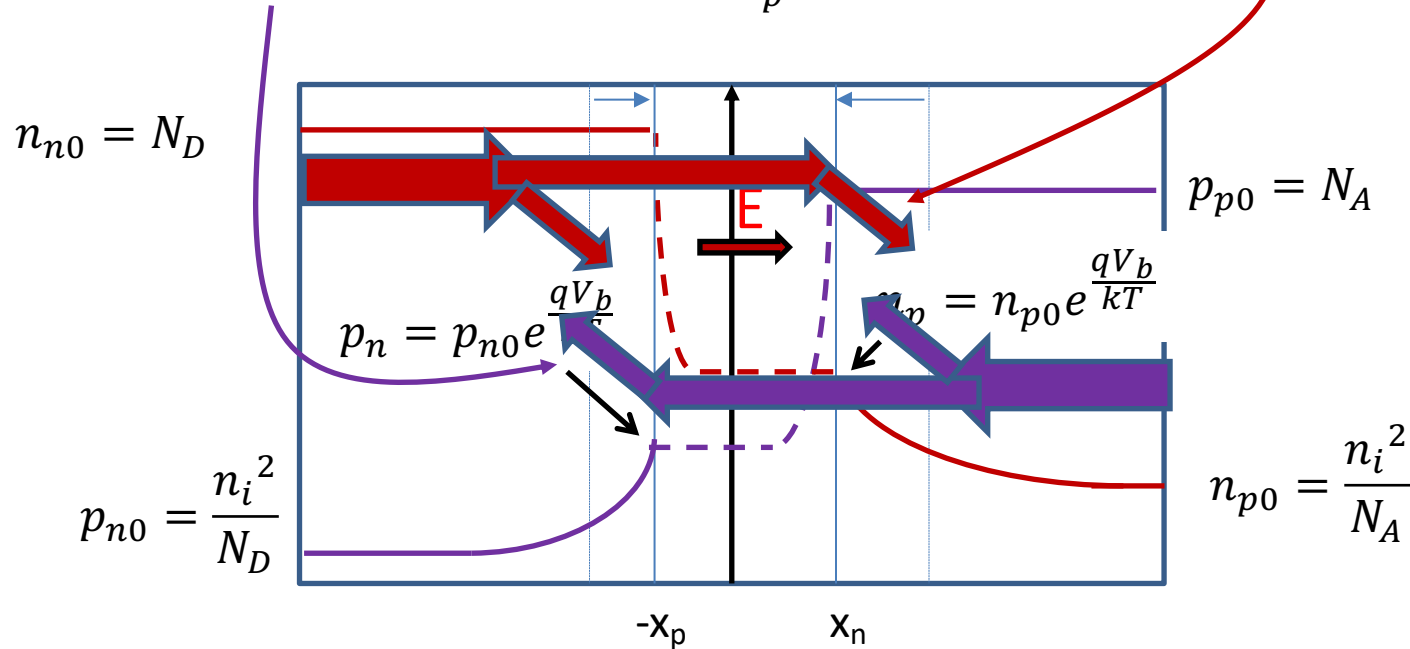
8.1 pn Junction Current

- charge carrier transport: forward bias

$$J_{n,diff} = qD_n \frac{dn_p}{dx} = -\frac{qD_n n_{p0}}{L_n} \left(e^{\frac{qV_a}{kT}} - 1 \right) e^{\frac{x_n - x}{L_n}}$$

$$J_{p,diff} = -qD_p \frac{dp_n}{dx} = -\frac{qD_p p_{n0}}{L_p} \left(e^{\frac{qV_a}{kT}} - 1 \right) e^{\frac{x + x_p}{L_p}}$$

$$J = J_n|_{x'=0} + J_n|_{x=0}$$



Assumption: No recombination-generation in depletion region.

8.1 pn Junction Current

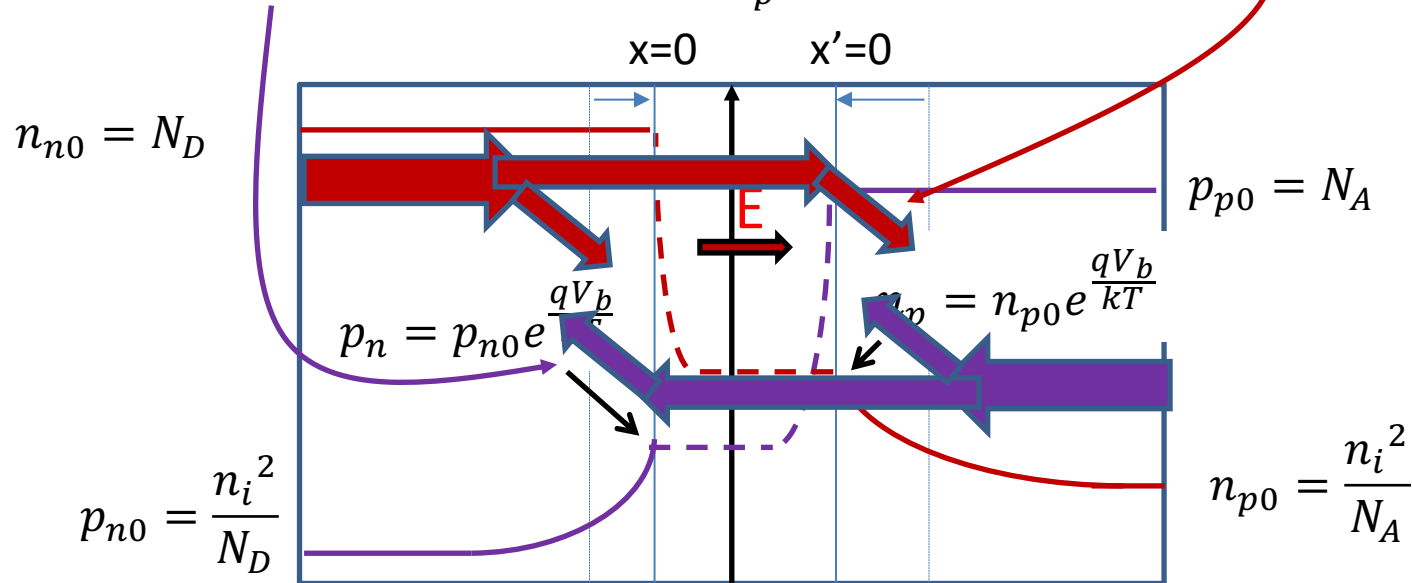
- Ideal pn junction current

8.1 pn Junction Current

- charge carrier transport: current ratio at forward bias (remember this, important)

$$J_n = qD_n \frac{dn_p}{dx} = -\frac{qD_n n_{p0}}{L_n} (e^{\frac{qV_b}{kT}} - 1)$$

$$J_p = -qD_p \frac{dp_n}{dx} = -\frac{qD_p p_{n0}}{L_p} (e^{\frac{qV_b}{kT}} - 1)$$



Assumption: No recombination-generation in depletion region.

8.1 pn Junction Current

- charge carrier transport: reverse bias

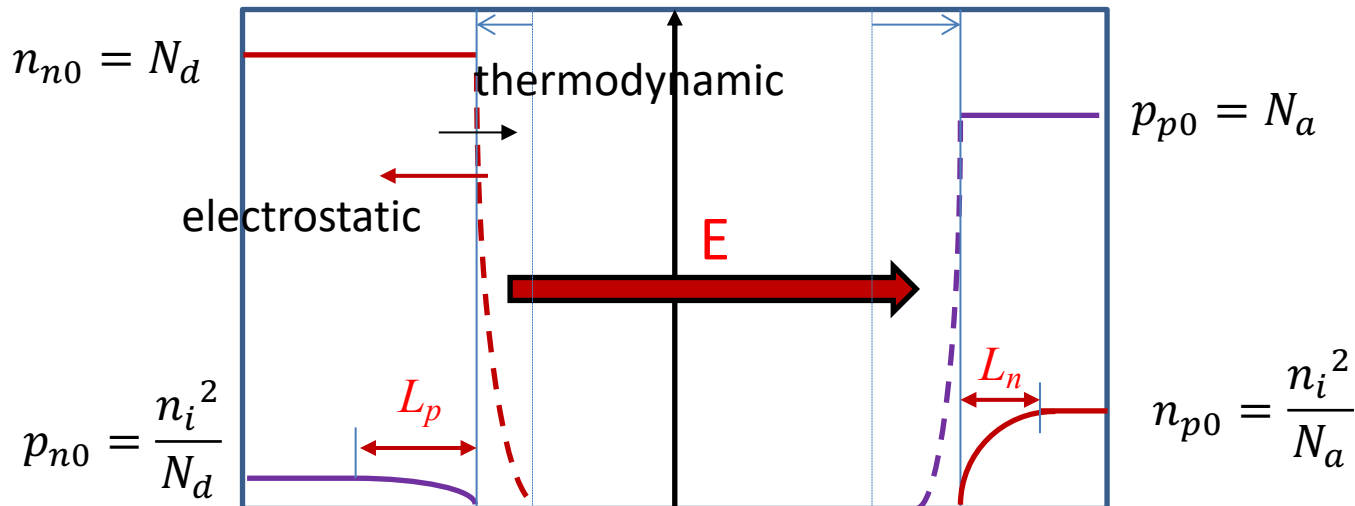
$$J_n = qD_n \frac{dn_p}{dx} = \frac{qD_n n_{p0}}{L_n}$$

$$J_p = -qD_p \frac{dp_n}{dx} = \frac{qD_p p_{n0}}{L_p}$$

$$J = J_n|_{x'=0} + J_n|_{x=0}$$

$$J = J_s \left(e^{\frac{qV_b}{kT}} - 1 \right) = -J_s$$

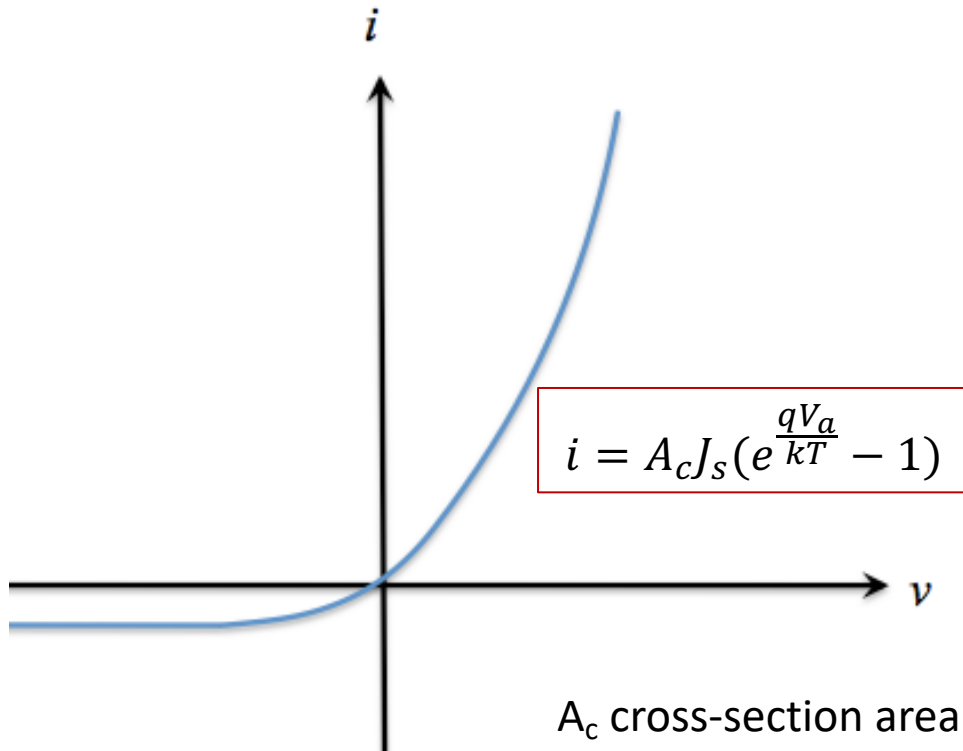
$$J_s = \frac{qD_n n_{p0}}{L_n} + \frac{qD_p p_{n0}}{L_p}$$



Assumption: No recombination-generation in depletion region.

8.1 pn Junction Current

- charge carrier transport: forward bias



$$J = J_n|_{x'=0} + J_n|_{x=0}$$

$$J = J_s (e^{\frac{qV_b}{kT}} - 1)$$

$$J_s = \frac{qD_n n_{p0}}{L_n} + \frac{qD_p p_{n0}}{L_p}$$

$$i = A_c J_s (e^{\frac{qV_a}{kT}} - 1)$$

Check your understanding

Problem Example #2

Given the following parameters in a silicon pn junction, determine the ideal reverse-saturation current density of this pn junction at 300K.

$$N_a = N_d = 10^{16} \text{ cm}^{-3}$$

$$n_i = 1.5 \times 10^{10} \text{ cm}^{-3}$$

$$D_n = 25 \text{ cm}^2/\text{s}$$

$$\tau_{p0} = \tau_{n0} = 5 \times 10^{-7} \text{ s}$$

$$D_p = 10 \text{ cm}^2/\text{s}$$

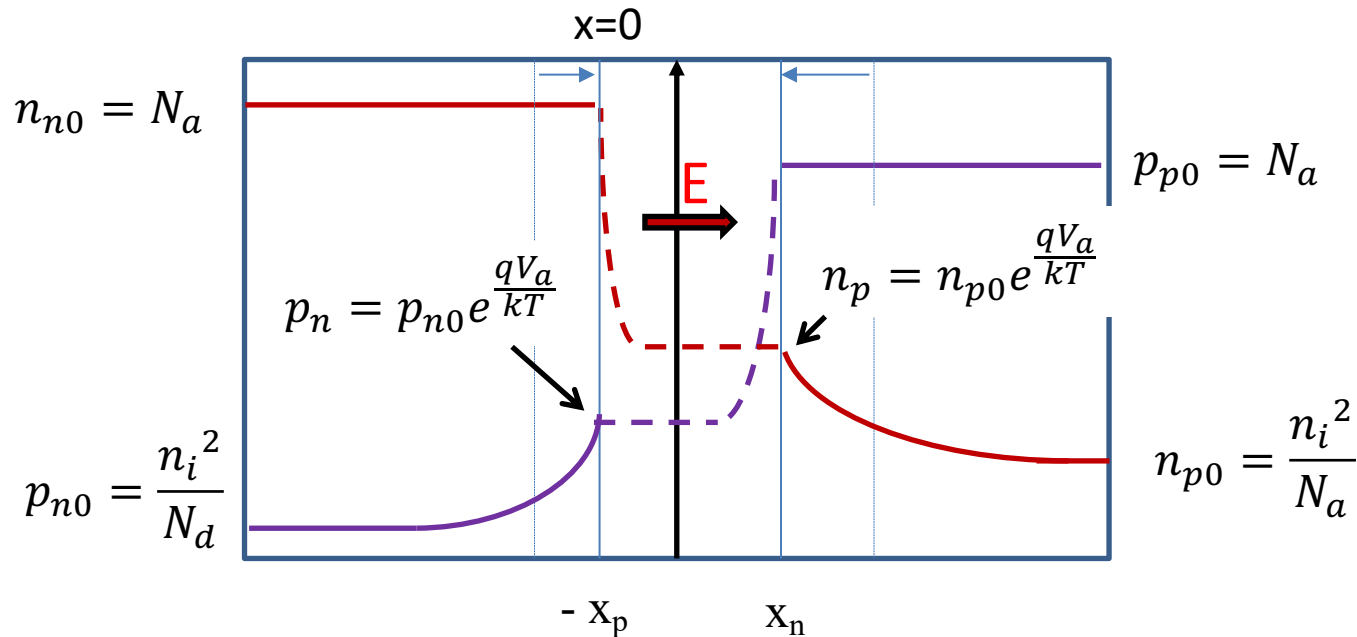
$$\epsilon_r = 11.7$$

8.1 pn Junction Current

Minority carrier distribution

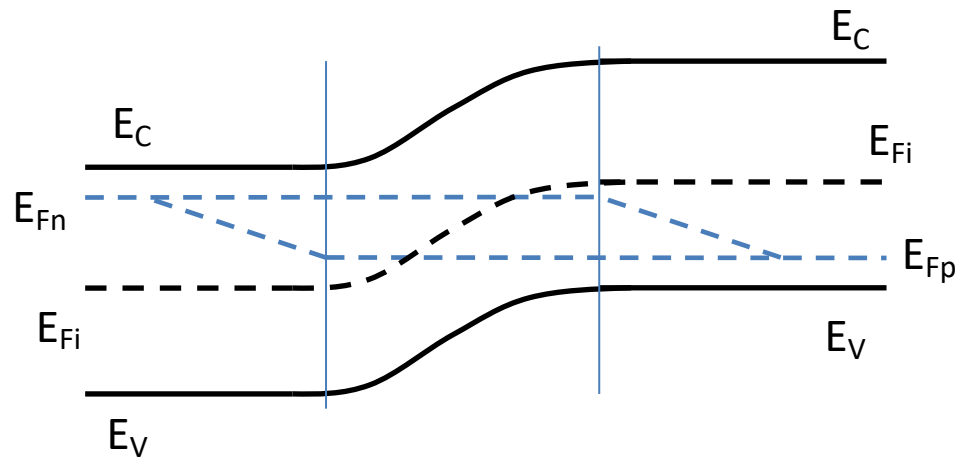
$$p = p_o + \delta p = n_i \exp\left(\frac{E_{Fi} - E_{Fp}}{kT}\right)$$

$$n = n_o + \delta n = n_i \exp\left(\frac{E_{Fn} - E_{Fi}}{kT}\right)$$



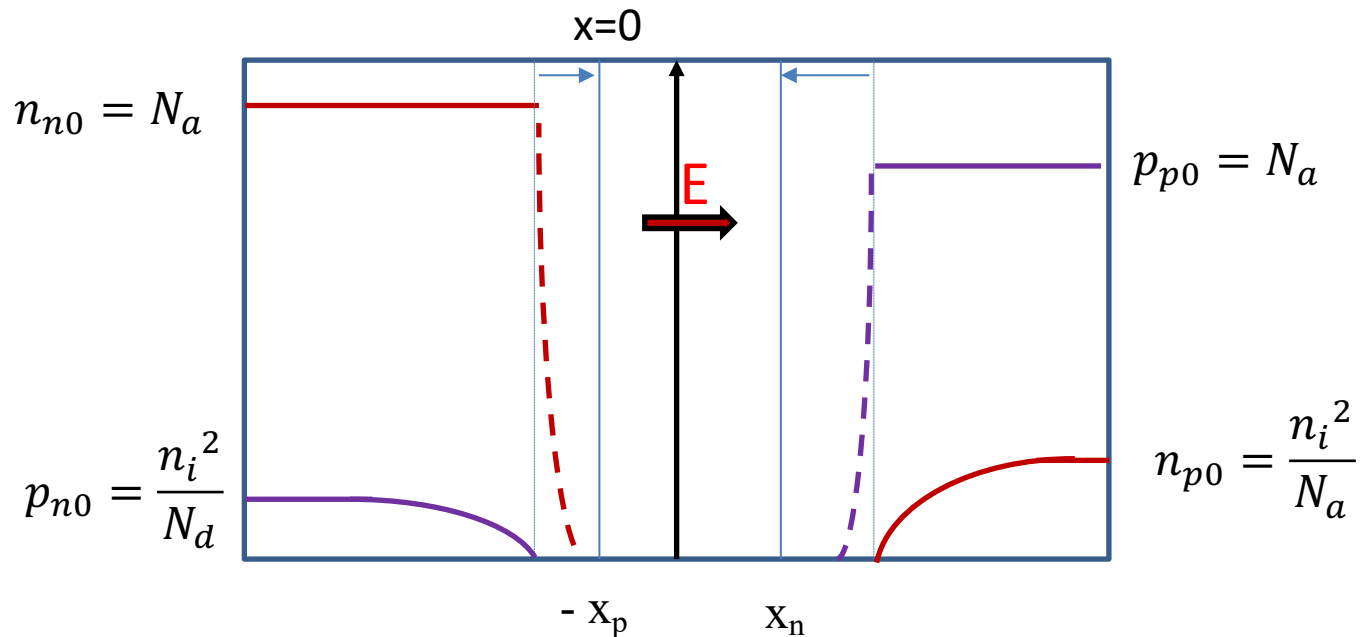
8.1 pn Junction Current

Minority carrier distribution (Quasi Fermi level on excess carrier distribution)



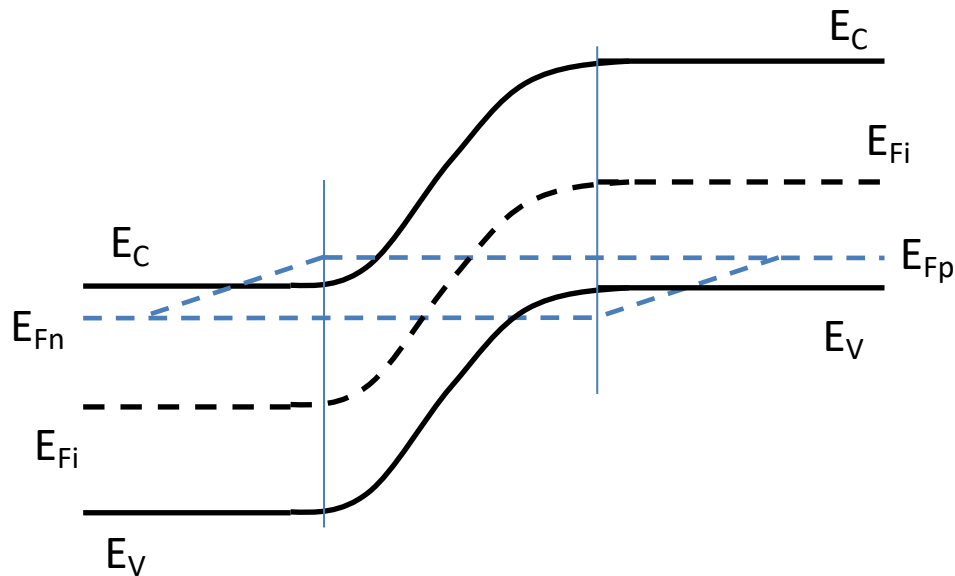
8.1 pn Junction Current

Minority carrier distribution (reverse bias)



8.1 pn Junction Current

Minority carrier distribution (Quasi Fermi level on carrier concentration)



Outline

8.1 pn junction current

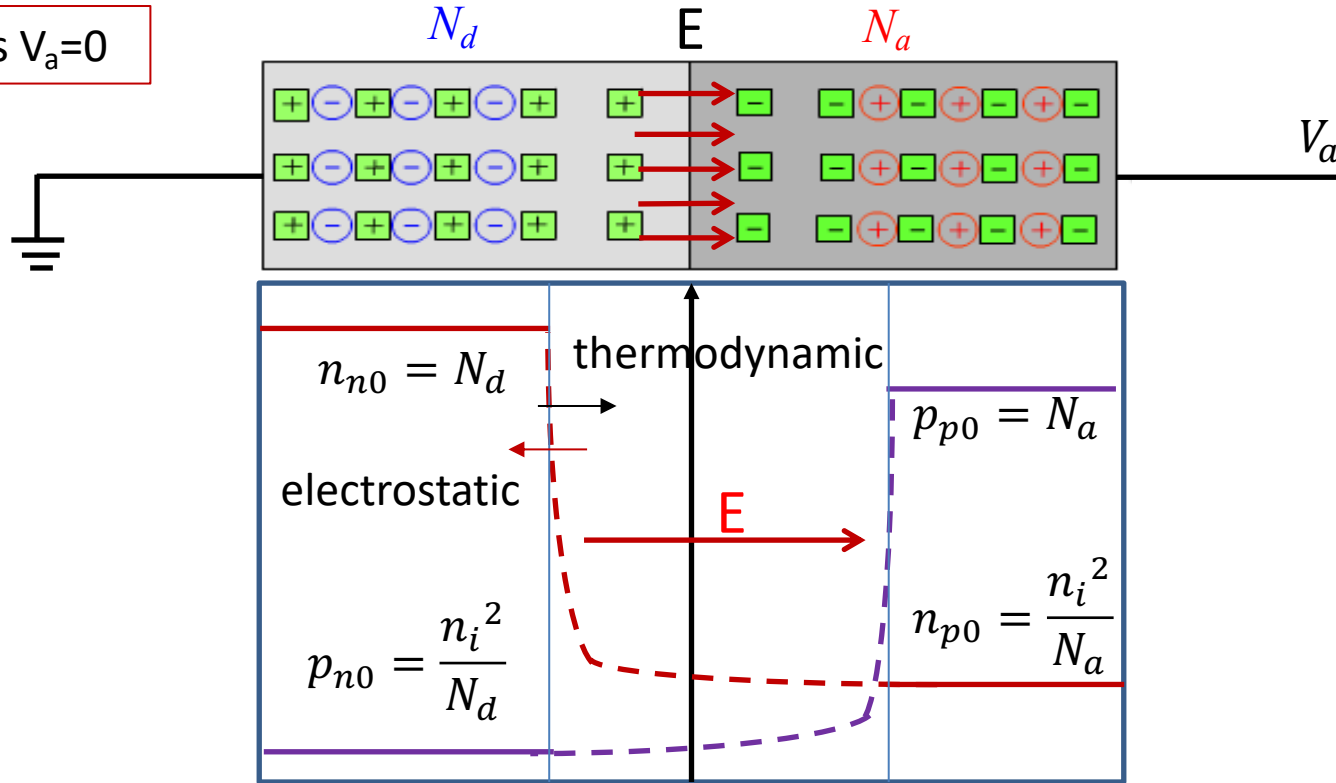
8.2 Generation-recombination currents

8.3 High-injection levels

8.4 A few more points on pn junctions (not in the textbook)

8.2 Generation-recombination currents

Zero Bias $V_a=0$

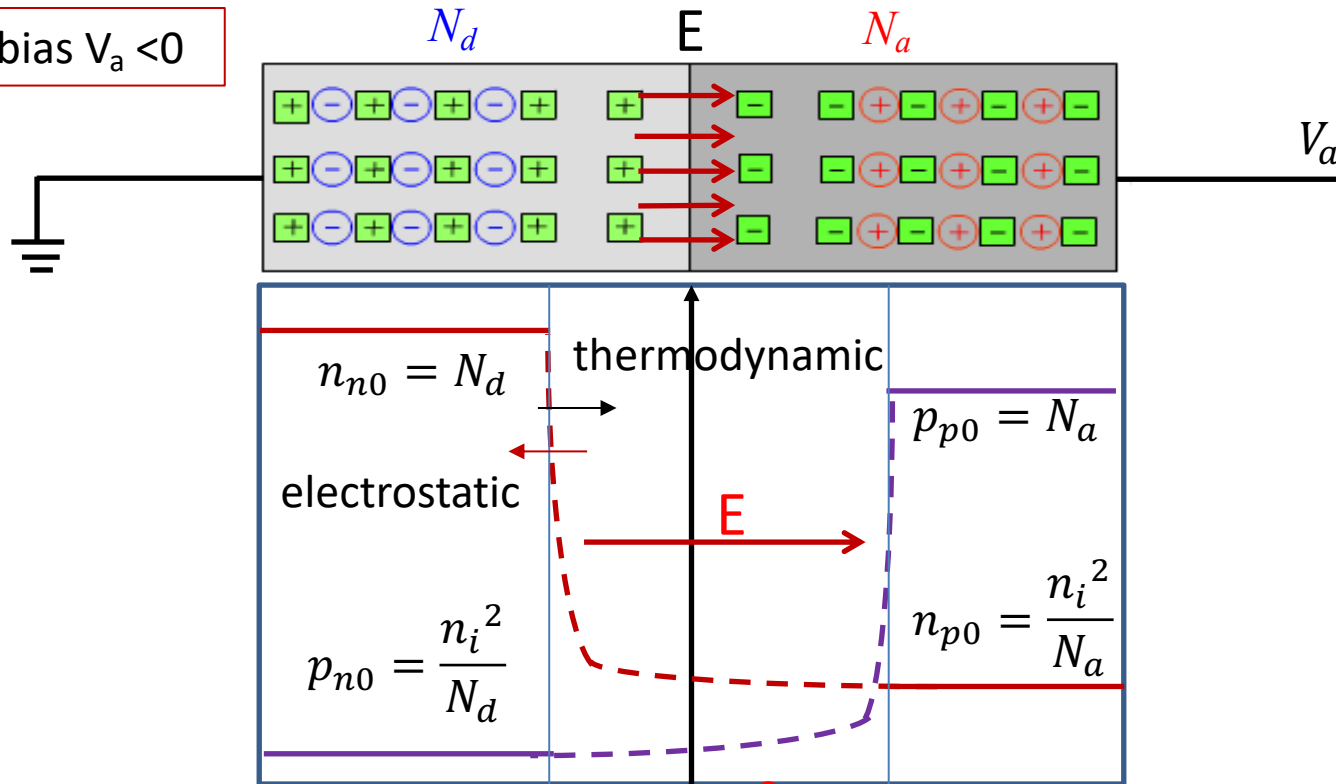


$$R_n = \frac{(np - n_i^2)}{\tau_p \left[n + n_i \exp\left(\frac{E_t - E_i}{kT}\right) \right] + \tau_n \left[p + n_i \exp\left(\frac{E_i - E_t}{kT}\right) \right]}$$

$$\text{In depletion region: } np = n_i^2 \exp\left(\frac{qV_a}{kT}\right)$$

8.2 Generation-recombination currents

Reverse bias $V_a < 0$



$$R_n = \frac{(np - n_i^2)}{\tau_p \left[n + n_i \exp\left(\frac{E_t - E_i}{kT}\right) \right] + \tau_n \left[p + n_i \exp\left(\frac{E_i - E_t}{kT}\right) \right]}$$

8.2 Generation-recombination currents

Reverse bias $V_a < 0$

To simplify the calculation, we assume

$$E_t = E_i, \tau_n = \tau_p = \tau$$

8.2 Generation-recombination currents

Reverse bias $V_a < 0$

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$$E_t = E_i, \tau_n = \tau_p = \tau$$

Current density from G-R in the depletion region:

8.2 Generation-recombination currents

Reverse bias $V_a < 0$

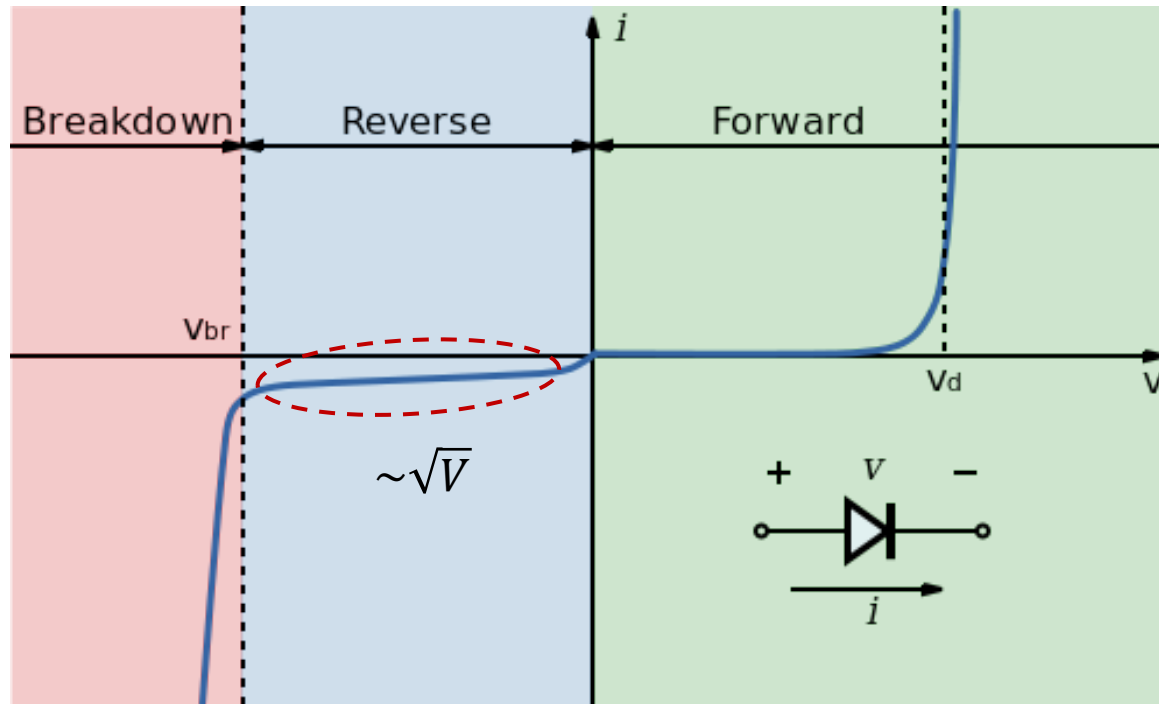
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Current density from G-R in the depletion region:

8.2 8.2 Generation-recombination currents

Reverse bias $V_a < 0$

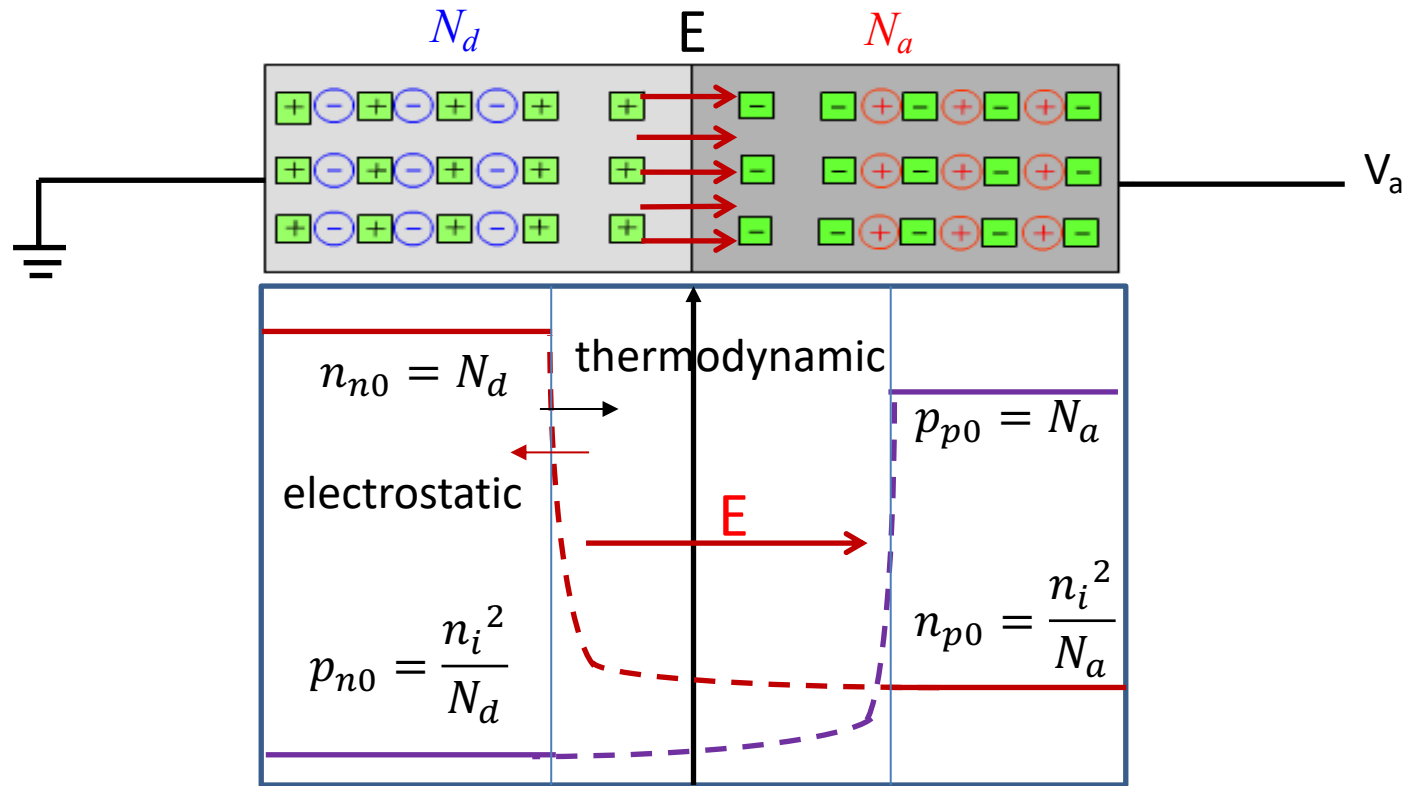


Current density from G-R in the depletion region:

$$J_r = \int_0^W qGdx = \frac{qWn_i}{2\tau}$$

$$W = a + b = \sqrt{\frac{2\epsilon(V_{bi} - V_a)}{q} \frac{N_d + N_a}{N_a N_d}}$$

8.2 Generation-recombination currents



In depletion region: $np = n_i^2 \exp\left(\frac{qV_a}{kT}\right)$

8.2 Generation-recombination currents

To simplify the calculation, we assume

$$E_t = E_i, \tau_n = \tau_p = \tau$$

When $n=p$, U reaches its max value.

8.2 Generation-recombination currents

Current density from G-R in the depletion region:

For a non-ideal pn junction, the total current density:

8.2 Generation-recombination currents

Forward bias $V > 3kT/q = 0.078V$:

8.2 Generation-recombination currents

Check your understanding

Problem Example #3

An n-type semiconductor (10^{17}cm^{-3}) is in contact with another p-type semiconductor (10^{17}cm^{-3}). Suppose a silicon PN junction has defects located at the middle of the bangap. The defect concentration is 10^{16}cm^{-3} and the capture rate C_n and C_p for electrons and holes are $10^{-10}\text{cm}^{-3}/\text{s}$. Find the leakage current of the Si PN junction if the pn junction is reverse biased at 1V ($V_R=1\text{V}$) .



Depletion region

$$N_t = 10^{16}\text{cm}^{-3}$$
$$C_n = C_p = 10^{-10}\text{cm}^{-3}/\text{s}$$

Outline

8.1 pn junction current

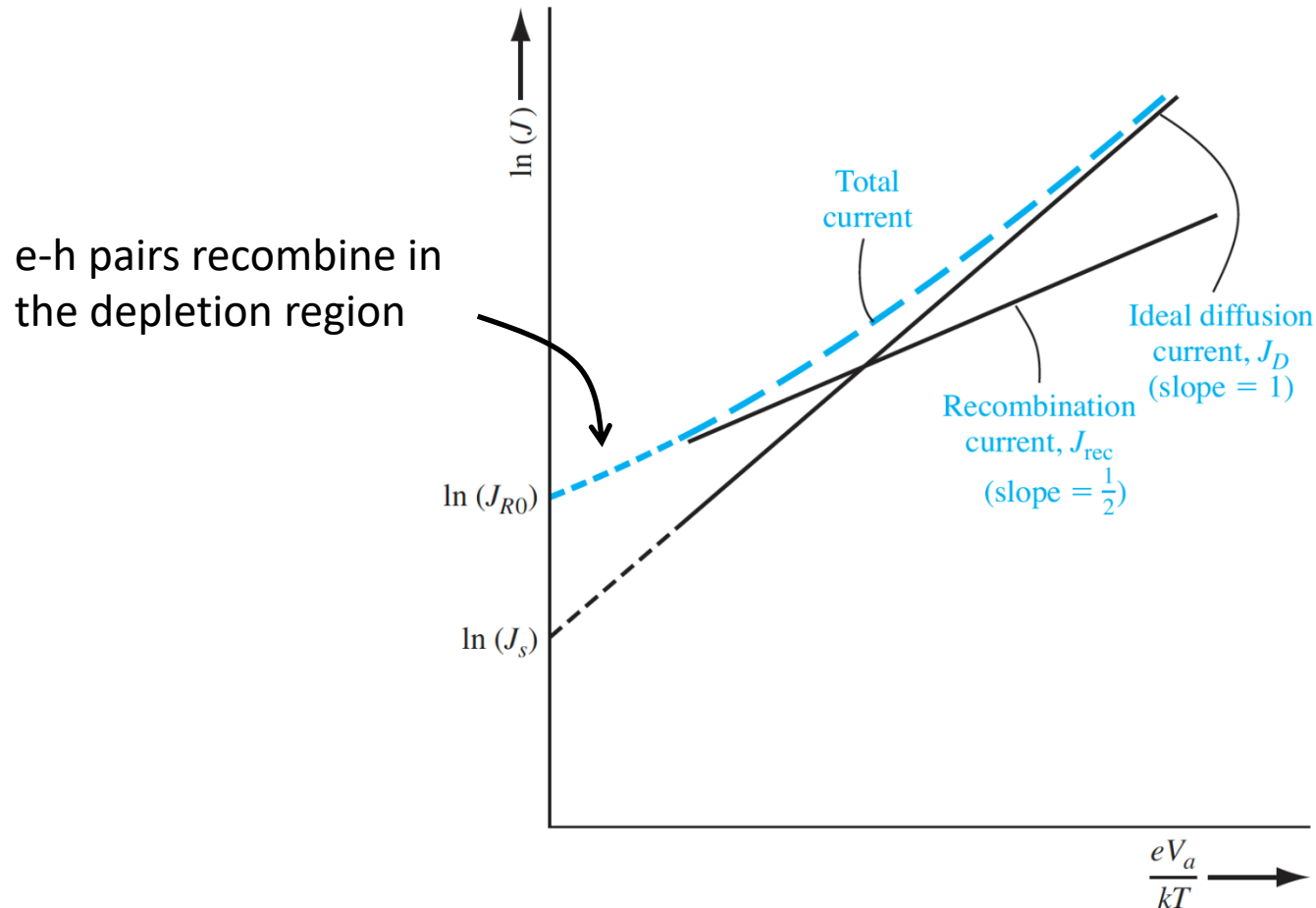
8.2 Generation-recombination currents

8.3 High-injection levels

8.4 A few more points on pn junctions (not in the textbook)

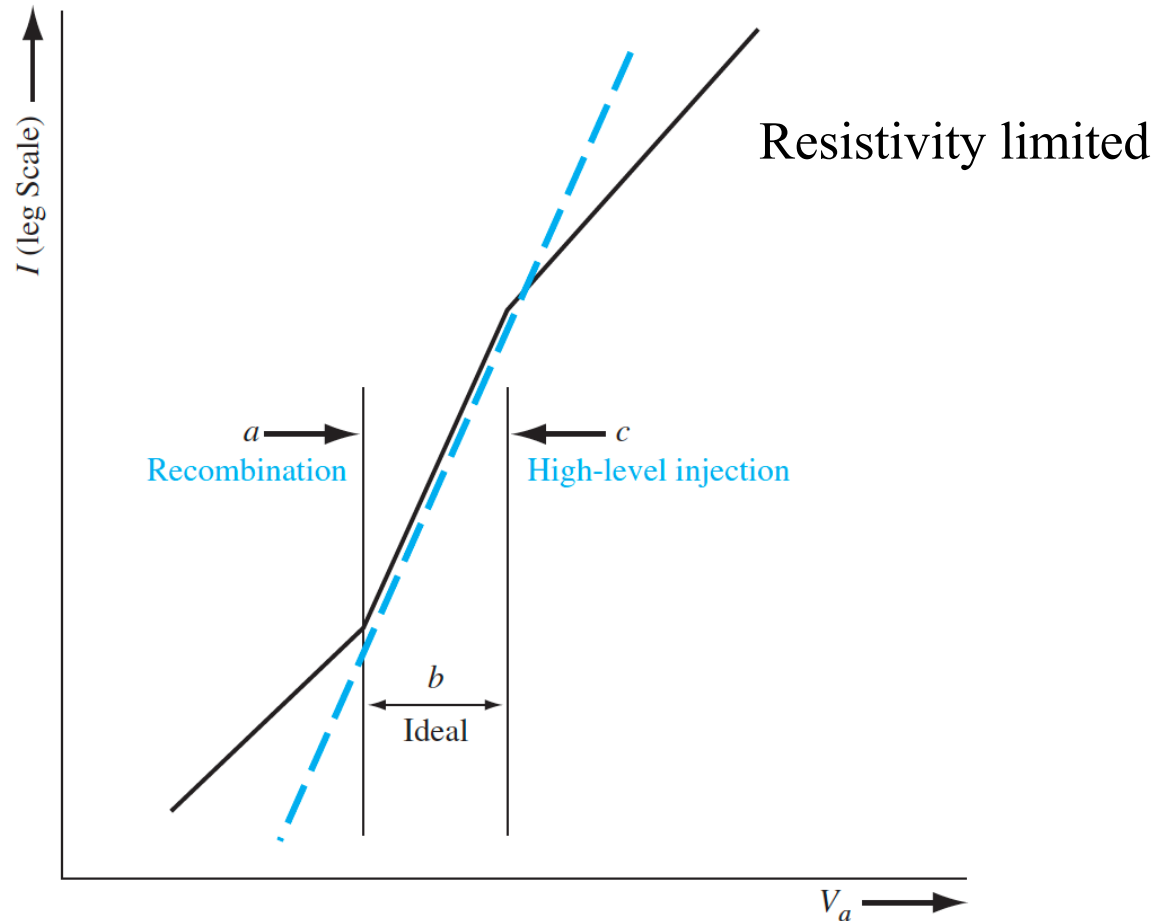
8.3 High inject level

$$J = J_F + J_r = J_s \exp\left(\frac{qV_a}{kT}\right) + \frac{qWn_i}{2\tau} \exp\left(\frac{qV_a}{2kT}\right) = J_0 \exp\left(\frac{qV_a}{nkT}\right)$$



8.3 High inject level

$$J = J_F + J_r = J_s \exp\left(\frac{qV_a}{kT}\right) + \frac{qWn_i}{2\tau} \exp\left(\frac{qV_a}{2kT}\right) = J_0 \exp\left(\frac{qV_a}{nkT}\right)$$



Outline

8.1 pn junction current

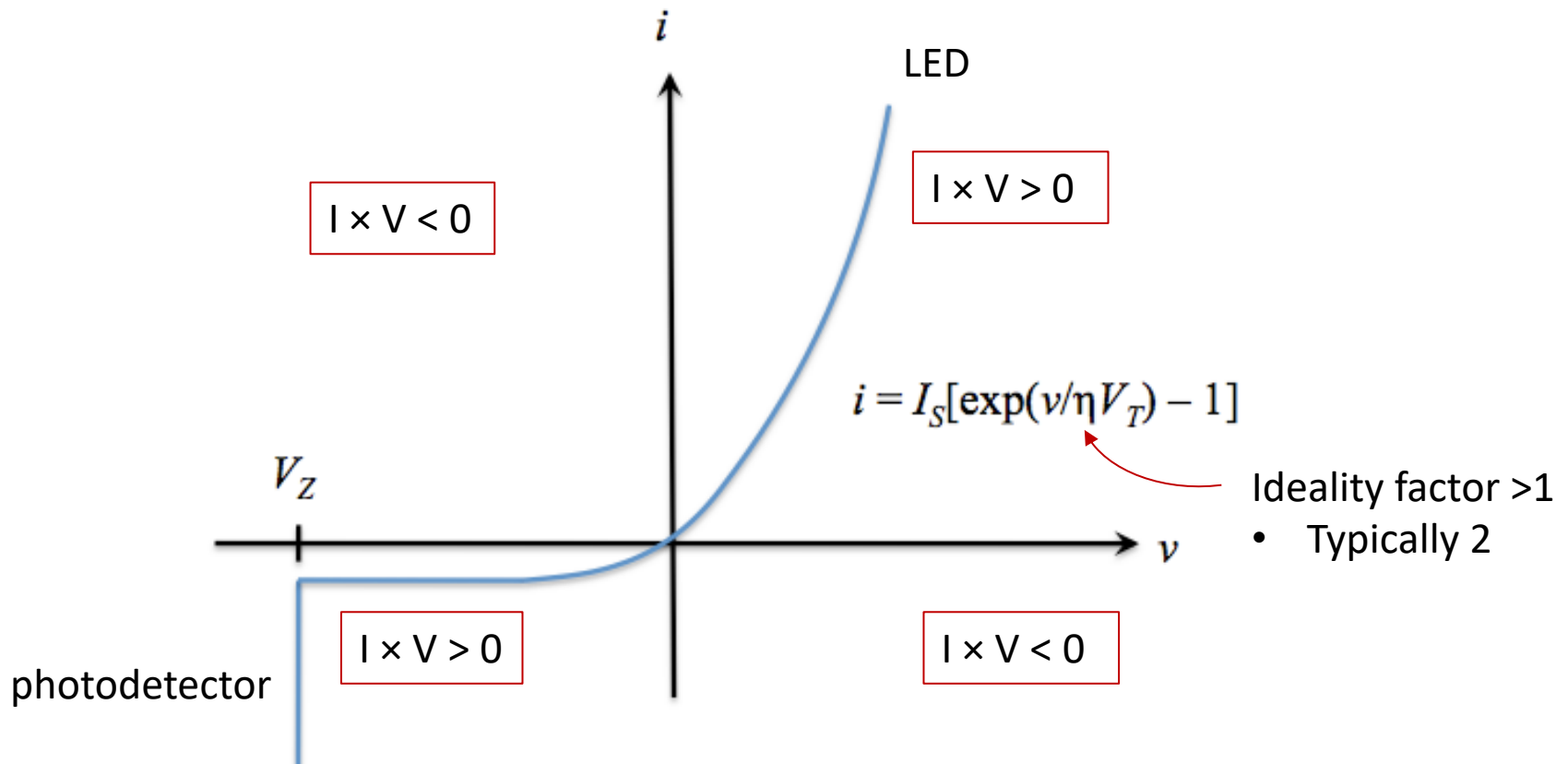
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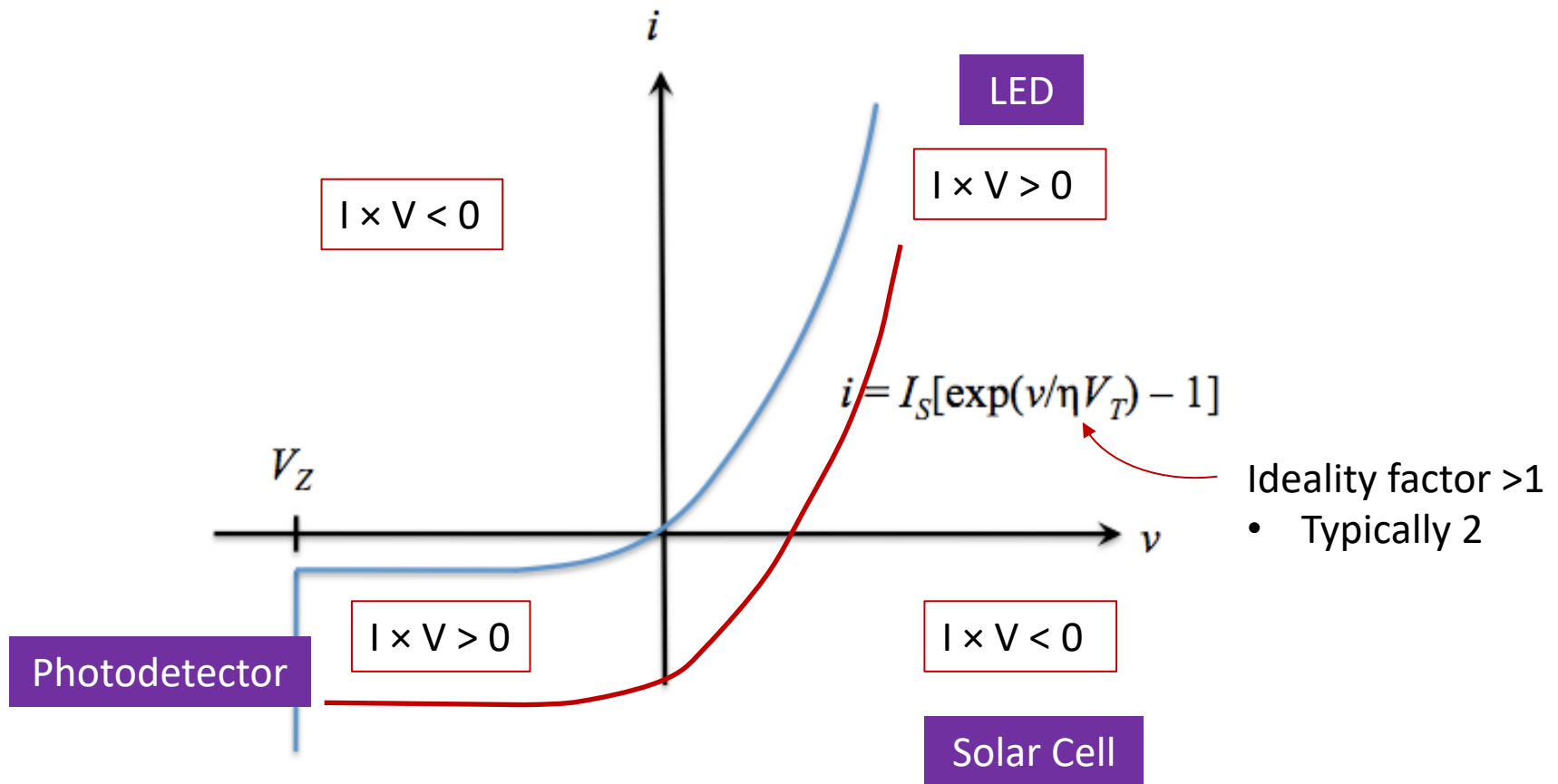
8.4 A few points about pn junction

- Energy consumption:

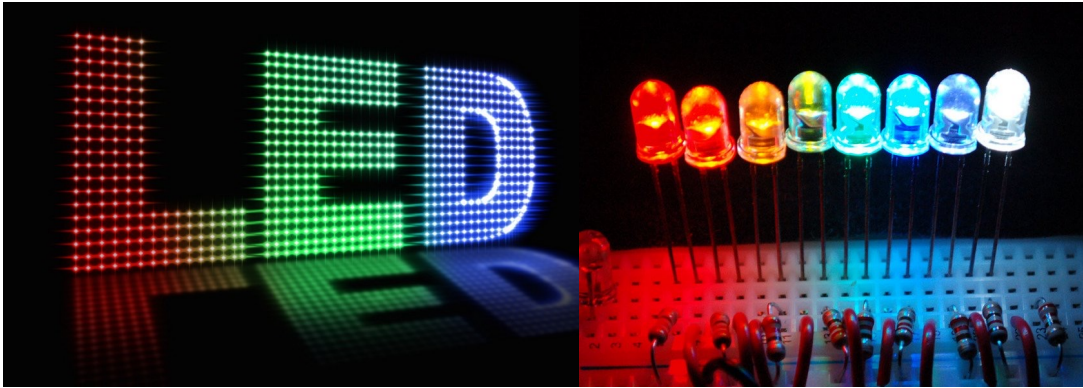


8.4 A few points about pn junction

- Energy consumption:



Introduction to semiconductor devices

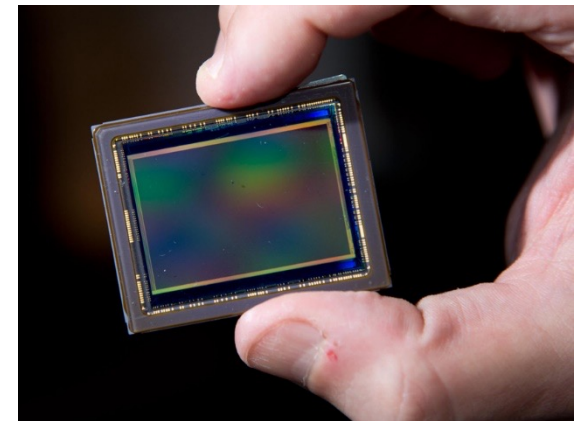
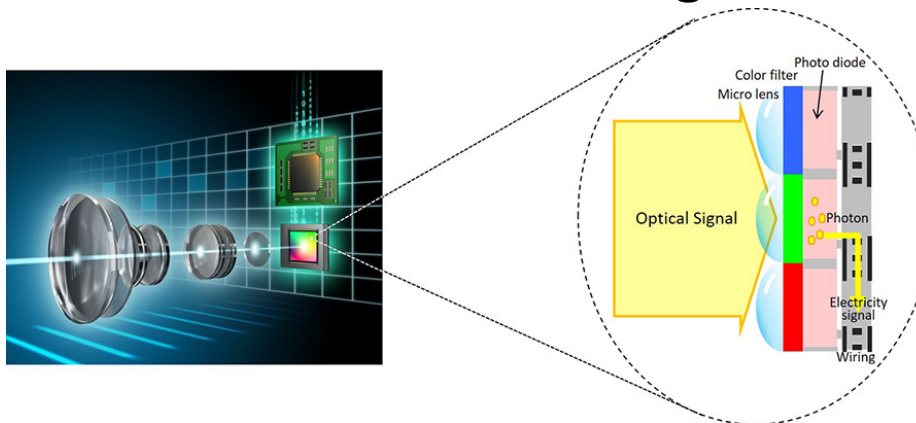


Light emitting diodes

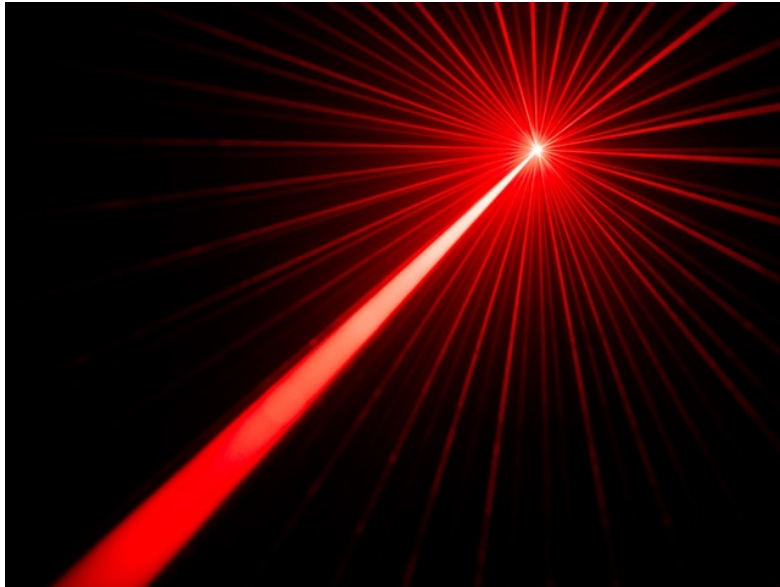


Cold light source

Photodetector: CMOS image sensor



Introduction to semiconductor devices



Semiconductor lasers



Solar cells